

# Corrections

## Corrections to “Physically Rigorous Modeling of Internal Laser-Probing Techniques for Microstructured Semiconductor Devices”

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The following typesetting errors are in the original version of this article published in [1].

- Equation (9) on p. 63 and equation (37) on p. 68 should be

$$M_{k,2}U(z_{k+1}) = M_{k,1}U(z_k). \quad (1)$$

- The reference in the fourth line of the last paragraph on p. 65 should be Fig. 6.
- On p. 63, the subsections of Section II-C2 “Boundary Conditions in Propagation Direction,” should be:
  - a) *Boundary condition in the  $k_x$ - $z$ -space;*
  - b) *Matrix representation of the boundary conditions in real space.*
- In the Appendix, the correct plot for Fig. 12 is missing. Fig. 12 is reprinted here.
- In the Appendix, the section numbering was incorrect. The Appendix should be as follows.

### APPENDIX A PROPAGATOR MATRICES

To derive the propagator matrix, (7) and (8) are integrated analytically over the interval  $[z_k, z_{k+1}]$ , assuming a linear interpolation of the computational variables  $E^{F,B}$  and the dielectric constant  $\varepsilon_R$ . The resulting summands comprise products of  $E^{F,B}(x, z_{k,k+1})$ ,  $\varepsilon_R(x, z_{k,k+1})$ , and  $e^{i\kappa z_{k,k+1}}$ . Sorting by  $E^{F,B}(x, z_k)$  and  $E^{F,B}(x, z_{k+1})$  transforms (7) and (8) to a matrix equation of the following form:

$$\begin{pmatrix} A_k(x) - \frac{i\Delta z_k}{4\kappa} \partial_x^2 & B_k(x) + K_k \partial_x^2 \\ C_k(x) + K_k^* \partial_x^2 & D_k(x) + \frac{i\Delta z_k}{4\kappa} \partial_x^2 \end{pmatrix} \begin{pmatrix} E^F(x, z_{k+1}) \\ E^B(x, z_{k+1}) \end{pmatrix} \\ = \begin{pmatrix} \tilde{A}_k(x) + \frac{i\Delta z_k}{4\kappa} \partial_x^2 & \tilde{B}_k(x) + \tilde{K}_k \partial_x^2 \\ \tilde{C}_k(x) + \tilde{K}_k^* \partial_x^2 & \tilde{D}_k(x) - \frac{i\Delta z_k}{4\kappa} \partial_x^2 \end{pmatrix} \begin{pmatrix} E^F(x, z_k) \\ E^B(x, z_k) \end{pmatrix}. \quad (33)$$

In this equation, the constants  $K_k$  and  $\tilde{K}_k$  are functions of  $\omega$ ,  $\kappa$ ,  $z_k$ , and  $z_{k+1}$ , while  $A_k(x)$ ,  $B_k(x)$ ,  $C_k(x)$ ,  $D_k(x)$ ,  $\tilde{A}_k(x)$ ,  $\tilde{B}_k(x)$ ,  $\tilde{C}_k(x)$ , and  $\tilde{D}_k(x)$  additionally depend on  $\varepsilon_R(x, z_k)$  and  $\varepsilon_R(x, z_{k+1})$ .

Finite difference discretization at  $x = x_j$  yields three terms at each side of the equation referring to the positions  $x_{j-1}$ ,  $x_j$ , and  $x_{j+1}$

$$M_{k,j}^1 U(x_{j+1}, z_{k+1}) + M_{k,j}^2 U(x_j, z_{k+1}) + M_{k,j}^3 U(x_{j-1}, z_{k+1}) \\ = M_{k,j}^4 U(x_{j+1}, z_k) + M_{k,j}^5 U(x_j, z_k) + M_{k,j}^6 U(x_{j-1}, z_k)$$

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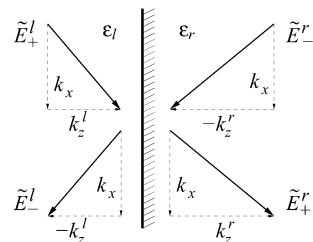


Fig. 12. Impinging and emerging waves with wave vector component  $k_x$  at an interface  $z = 0$  between two regions of different dielectric constants.

$$(34)$$

with

$$U(x_j, z_k) = \begin{pmatrix} E^F(x_j, z_k) \\ E^B(x_j, z_k) \end{pmatrix}. \quad (35)$$

The complex  $2 \times 2$  matrices  $M_{k,j}^{1,\dots,6}$  can be straightforwardly derived from (33). Defining the vector of unknowns [cf. (10)] by

$$U(z_k) = \left( E^F(x_1, z_k), E^B(x_1, z_k), \dots, E^F(x_{N_x}, z_k), E^B(x_{N_x}, z_k) \right)^T \quad (36)$$

we finally obtain the relation

$$M_{k,2}U(z_{k+1}) = M_{k,1}U(z_k). \quad (37)$$

With the complex  $2 \times 2$  matrices  $M_{k,j}^{1,\dots,6}$  [cf. (34)] as their coefficients, the matrices  $M_{k,2}$  and  $M_{k,1}$  are band structured with only one occupied superdiagonal and subdiagonal line. Thus, the propagator matrices  $P_k = M_{k,2}^{-1}M_{k,1}$  can be calculated very efficiently by multiplying band-structured matrices.

### APPENDIX B BOUNDARY CONDITIONS IN PROPAGATION DIRECTION

The impinging and emerging waves at an interface between the regions with dielectric constants  $\varepsilon_{l,r}$  (cf. Fig. 12) are related by the refraction law [44]

$$\begin{pmatrix} \tilde{E}_+^l(k_x, 0) \\ \tilde{E}_-^l(k_x, 0) \end{pmatrix} = \begin{pmatrix} \frac{k_z^l + k_z^r}{2k_z^l} & \frac{k_z^l - k_z^r}{2k_z^l} \\ \frac{k_z^l - k_z^r}{2k_z^l} & \frac{k_z^l + k_z^r}{2k_z^l} \end{pmatrix} \begin{pmatrix} \tilde{E}_+^r(k_x, 0) \\ \tilde{E}_-^r(k_x, 0) \end{pmatrix} \quad (38)$$

with  $k_z^{l,r} = \sqrt{\varepsilon_{l,r}k_0^2 - k_x^2}$ . To derive the boundary conditions, the travelling waves have to be expressed in terms of the electric field  $E_y$  and the magnetic field  $B_x$  and finally in terms of the computational variables  $\tilde{E}^F$  and  $\tilde{E}^B$  [cf. (6)].

At the entrance plane  $z = z_1$ , the field  $\tilde{E}_+^l$  is equal to the incident field  $\tilde{E}_i$ , while  $\tilde{E}_-^l$  represents the unknown reflected wave.  $\varepsilon_l$  is given by the dielectric constant  $\varepsilon_a$  in front of the entrance plane (i.e., for  $z < z_1$ ). We thus get the boundary condition at the left hand boundary of the simulation domain (12) and the conditional equation of the reflected wave (13) with  $k_z^a = \sqrt{\varepsilon_a k_0^2 - k_x^2}$ .

For a compact notation, the components  $\tilde{E}_i(k_x)$ ,  $\tilde{E}_r(k_x)$ , and  $\tilde{E}_t(k_x)$  are summarized in the vectors  $\tilde{\mathbf{E}}_i$ ,  $\tilde{\mathbf{E}}_r$ , and  $\tilde{\mathbf{E}}_t$ , respectively. Defining  $N_x \times 2N_x$  matrices  $\tilde{B}_{\pm}^{a,b}$  by

$$\begin{aligned} \left[ \tilde{B}_{\pm}^{a,b} \right]_{i,2i} &:= \frac{1}{2} \left( 1 \pm \frac{\kappa}{k_z^{a,b}} \right) \\ \left[ \tilde{B}_{\pm}^{a,b} \right]_{i,2i+1} &:= \frac{1}{2} \left( 1 \mp \frac{\kappa}{k_z^{a,b}} \right), \quad \text{for } i = 1, \dots, N_x \\ \left[ \tilde{B}_{\pm}^{a,b} \right]_{i,j} &:= 0, \quad \text{otherwise} \end{aligned} \quad (39)$$

transforms the boundary conditions to the form listed in (14).

#### REFERENCES

- [1] R. K. Thalhammer and G. K. M. Wachutka, "Physically rigorous modeling of internal laser-probing techniques for microstructured semiconductor devices," *IEEE Trans. Computer-Aided Design*, vol. 23, pp. 60–70, Jan. 2004.